Personality Traits Classification Using Deep Visual Activity-based Nonverbal Features of Key-Dynamic Images
Supplementary Material

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TABLE 1: The classification performance of the proposed method (%) in terms of the percentages of true positives (TP), true negatives (TN), false positives (FP) and false negatives (FN) for each personality trait of ELEA-AV [1] and ChaLearn [2] datasets. Positive class is the low-personality trait and negative class is the high-personality trait.

ELEA-AV [1]	TP	TN	FN	FP
Extraversion	0.84	0.72	0.16	0.29
Agreeableness	0.66	0.93	0.34	0.08
Conscientiousness	0.62	0.77	0.38	0.24
Emotional Stability	0.66	0.68	0.34	0.33
Openness	0.70	0.67	0.3	0.33
ChaLearn First Impression [2]	**TP**	**TN**	**FN**	**FP**
Extraversion	0.87	0.74	0.14	0.27
Agreeableness	0.71	0.86	0.30	0.15
Conscientiousness	0.95	0.58	0.06	0.43
Neuroticism	0.67	0.90	0.34	0.11
Openness	0.64	0.89	0.37	0.12

This supplemental material reports the classification results of the proposed method in terms of the percentages of true positives (TP), true negatives (TN), false positives (FP) and false negatives (FN) for each personality trait of ELEA-AV [1] and ChaLearn [2] datasets.

REFERENCES

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